

Qualification Results Summary for ADuM2210/ADuM2211 Die Revision and Data Sheet Change (SOIC_W)

QUALIFICATION PLAN / STATUS			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
High Temperature Operating Life (HTOL)*	JEDEC <i>JESD22-A108</i>	9x77	Pass
Highly Accelerated Stress Test (HAST)*	JEDEC <i>JESD22-A110</i>	5x32 4x77	Pass
Temperature Cycle (TC)*	JEDEC <i>JESD22-A104</i>	8x77 1x45	Pass
Autoclave (AC)*	JEDEC <i>JESD22-A102</i>	9x77	Pass
High Temperature Storage Life (HTSL)	JEDEC <i>JESD22-A103</i>	3x45 6x77	Pass
Latch-Up	JEDEC <i>JESD78</i>	1x9	Pass ±200mA @ +8.25V
Electrostatic Discharge <i>Human Body Model</i>	ESDA/JEDEC <i>JS-001</i>	1x18	Pass ±4000V
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JESD22-C101</i>	1x18	Pass ±1250V

*Preconditioned per JEDEC/IPC J-STD-020